

<<微观组织的分析电子显微学表征>>

图书基本信息

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作者：戎咏华

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内容概要

本书系统地介绍了分析电子显微学（AEM）的基本概念和操作技术，聚集于相变和形变中位错的AEM研究。同时通过大量的例子阐述衍射晶体学的物理概念和数学分析方法，例如相变中位向关系的定量预测等，以便读者加深理解和拓展视野。

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